

<b>Notice of References Cited</b>		Application/Control No. 10/572,506	Applicant(s)/Patent Under Reexamination JEON ET AL.	
		Examiner Kwang Han	Art Unit 1795	Page 1 of 1

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*	B	US-5,279,623	01-1994	Watanabe et al.	29/25.03
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